2SC4835G

Silicon NPN epitaxial planar type

For UHF band low-noise amplification

■ Features

- Low noise figure NF
- High forward transfer gain $|S_{21e}|^2$
- High transition frequency f_T
- S-Mini type package, allowing downsizing of the equipment and automatic insertion through the tape packing and the magazine packing

■ Absolute Maximum Ratings $T_a = 25$ °C

Parameter	Symbol	Rating	Unit	
Collector-base voltage (Emitter open)	V _{CBO}	15	V	
Collector-emitter voltage (Base open)	V _{CEO}	V _{CEO} 10		
Emitter-base voltage (Collector open)	V_{EBO}	2	V	
Collector current	I_{C}	80	mA	
Collector power dissipation	P _C	150	mW	
Junction temperature	T _j	150	°C	
Storage temperature	T_{stg}	-55 to +150	°C	

■ Package

- Code
 - SMini3-F2
- Marking Symbol: 3M
- Pin Name
 - 1: Base
 - 2: Emitter
 - 3: Collector

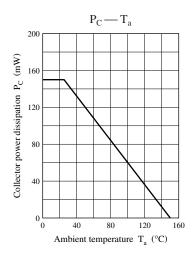
■ Electrical Characteristics $T_a = 25$ °C ± 3 °C

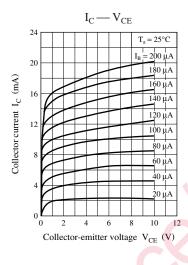
Parameter	Symbol	Conditions	Min	Тур	Max	Unit
Collector-base voltage (Emitter open)	V _{CBO}	$I_{\rm C} = 10 \; \mu \text{A}, I_{\rm E} = 0$	15			V
Collector-emitter voltage (Base open)	V _{CEO}	$I_C = 100 \mu\text{A}, I_B = 0$	10			V
Collector-base cutoff current (Emitter open)	I_{CBO}	$V_{CB} = 10 \text{ V}, I_{E} = 0$			1	μΑ
Emitter-base cutoff current (Collector open)	I _{EBO}	$V_{EB} = 2 \text{ V}, I_{C} = 0$			1	μΑ
Forward current transfer ratio *1,2	h _{FE}	$V_{CE} = 8 \text{ V}, I_{C} = 20 \text{ mA}$	50		200	_
Transition frequency	f_T	$V_{CE} = 8 \text{ V}, I_{C} = 15 \text{ mA}, f = 800 \text{ MHz}$	5	6		GHz
Collector output capacitance	C_{ob}	$V_{CB} = 10 \text{ V}, I_E = 0, f = 1 \text{ MHz}$		0.7	1.2	pF
(Common base, input open circuited)	(g)					
Forward transfer gain	$ S_{21e} ^2$	$V_{CE} = 8 \text{ V}, I_{C} = 15 \text{ mA}, f = 800 \text{ MHz}$	11	14		dB
Maximum unilateral power gain	G_{UM}	$V_{CE} = 8 \text{ V}, I_{C} = 15 \text{ mA}, f = 800 \text{ MHz}$		15		dB
Noise figure	NF	$V_{CE} = 8 \text{ V}, I_{C} = 7 \text{ mA}, f = 800 \text{ MHz}$		1.3	2.0	dB

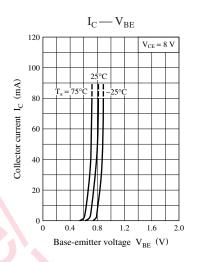
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

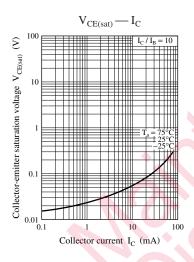
- 2. *1: Pulse measurement
 - *2: Rank classification

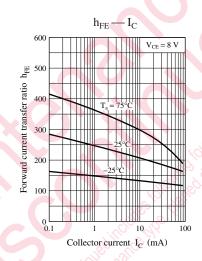
Rank	Q	R	S
h_{FE}	50 to 100	80 to 130	100 to 200

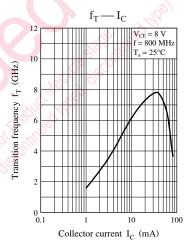


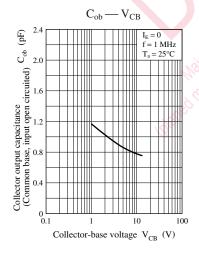


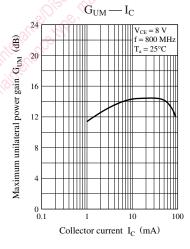


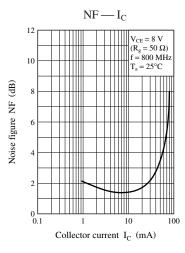






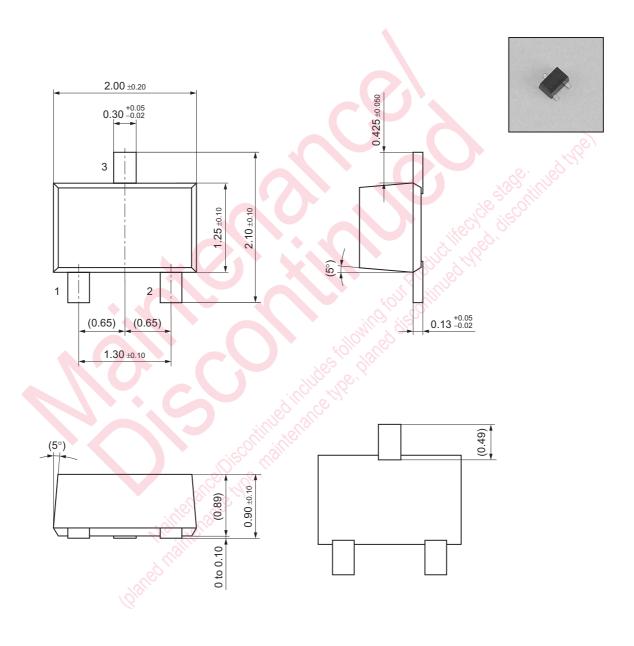






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SMini3-F2 Unit: mm



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